

Search Notes

Application/Control No.

10/767,768

Examiner

Thomas D. Lee

Applicant(s)/Patent under
Reexamination

OGAWA, HIDEHIKO

Art Unit

2624

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|-------------------|----------|----------|
| 358 | 1.15, 402, 440 | 6/7/2005 | TDL |
| 379 | 100.01 | 6/7/2005 | TDL |
| 379 | 100.08 | 6/7/2005 | TDL |
| 379 | 100.13 | 6/7/2005 | TDL |
| 379 | 100.17 | 6/7/2005 | TDL |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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